

# Non-contact thermophysical characterization of solids and fluids for Gen3 concentrating solar power

Generation 3 Concentrating Solar Power Systems

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Topic Area 2B - Gen3 Research and Analysis

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# Objectives and Impacts

- **Problem Statement**

- Challenging and time consuming to measure thermophysical properties of high-temperature HTFs, e.g., molten salts and particles.
- Lack of *in-situ* diagnostic tools to monitor thermophysical properties of HTFs

- **Objectives**

- Develop a non-contact technique based on “*modulated photothermal radiometry*” or “**MPR**”, to measure thermal conductivity ( $k$ ) and specific heat ( $C$ ) of **heat transfer fluids (HTFs), solar receiver tubes, coatings**, up to 800°C
- Use the tool for *in-situ* diagnostics of materials in CSP plants and of their corrosion behaviors.

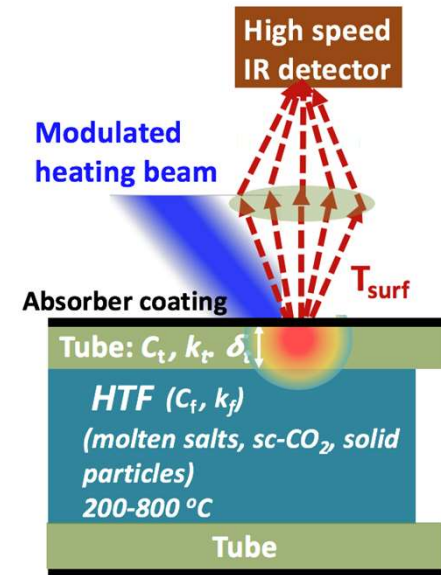
- **Impacts to Gen3 CSP**

- Facile and room-to-high temperature thermophysical measurements of emerging fluids (e.g., molten salts) and solids (e.g., particles) for Gen3 CSP systems.
- Transition of the diagnostics tool for laboratory and *in-situ* testing in other Gen3 awardees.

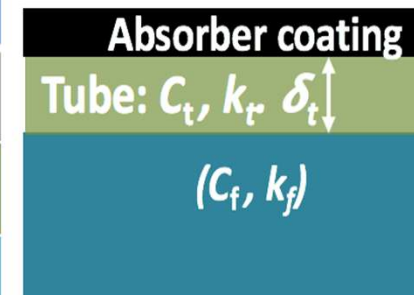
# Working Principles of MPR

## Key Principles and Merits

- By changing the modulation frequency and the thermal penetration depth of the heating beam, the surface temperature will be sensitive to  $k$  and  $C$  of different layers (HTF, tube, and coating).
- Lock-in technique for surface IR thermometry with **mK resolution**.
- Works for both rough and smooth surfaces (unlike thermoreflectance that requires a smooth surface)
- Suitable for high temperature measurements (IR emission is stronger at higher temperature)
- Non-contact, minimal sample preparation (fast), Low-cost



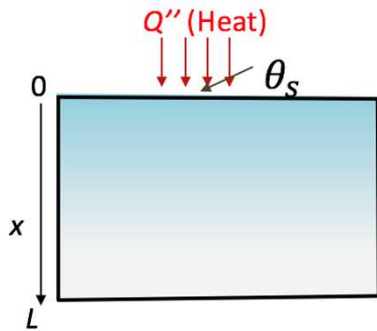
Layer	Rep. materials	$k@600^{\circ}\text{C}$ (W/m-K)	$C@600^{\circ}\text{C}$ (J/m <sup>3</sup> -K)	$\alpha@600^{\circ}\text{C}$ (m <sup>2</sup> /s)	Thickness (L)	Frequency (Hz)
Solar coating	Black oxide	1- 10 (?)	$\sim 0.5 - 2 \times 10^6$ (?)	$0.2-3 \times 10^{-6}$ (?)	>10 $\mu\text{m}$	> $\sim 60$ kHz
Tube shell	Inconel or Haynes	22	$5 \times 10^6$	$4.3 \times 10^{-6}$	0.5 mm	> $\sim 6$
HTF	Molten salt	$\sim 0.5$	$2.8 \times 10^6$	$1.8 \times 10^{-7}$	10 mm	0.1-6



Thermal penetration depth:  $L_p = \sqrt{2 \alpha / \omega}$

# Simultaneous Measurement of $k$ and $C$

- Using Modulated or Pulsed Photothermal Radiometry to measure  $k$  and  $C$  of thin films and bulks has already been demonstrated in the literature (e.g., refs 1-2).
- We can tune the spot and frequency to yield both  $k$  and  $C$ .
- Measurement sensitivity  $> 0.5$  within suitable frequency range.

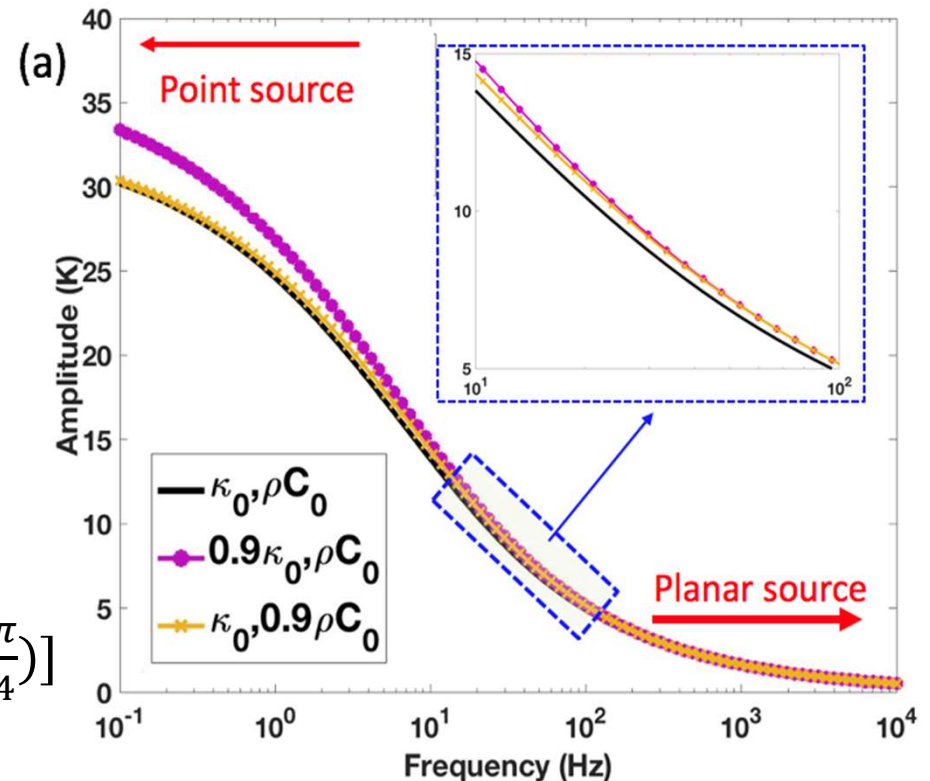


- Point heat source (spot size  $< L_p$ )

$$\theta_{s,point}(\omega) = \frac{Q_0}{2\pi\kappa r} \exp(i\omega t)$$

- Planar heat source (spot size  $> L_p$ )

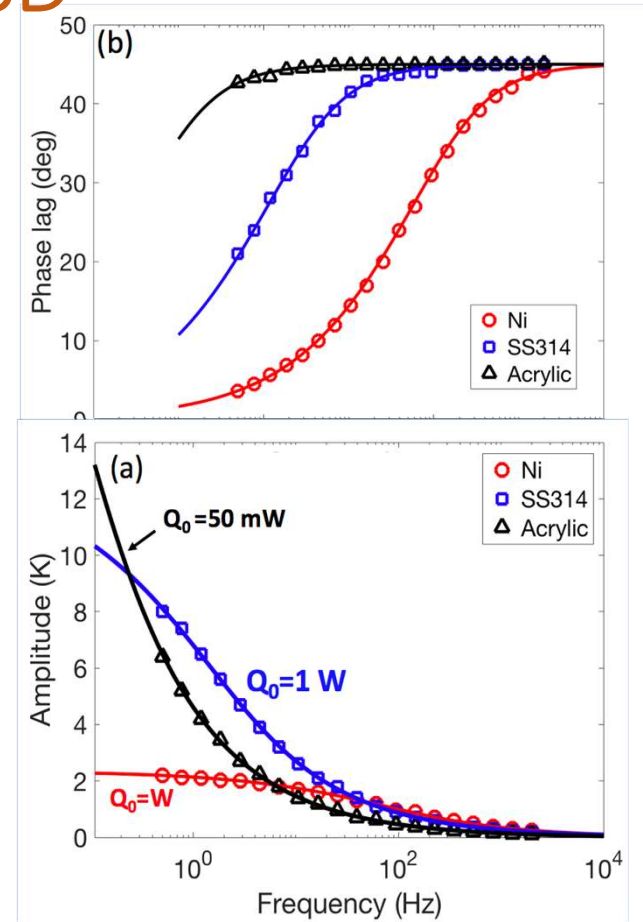
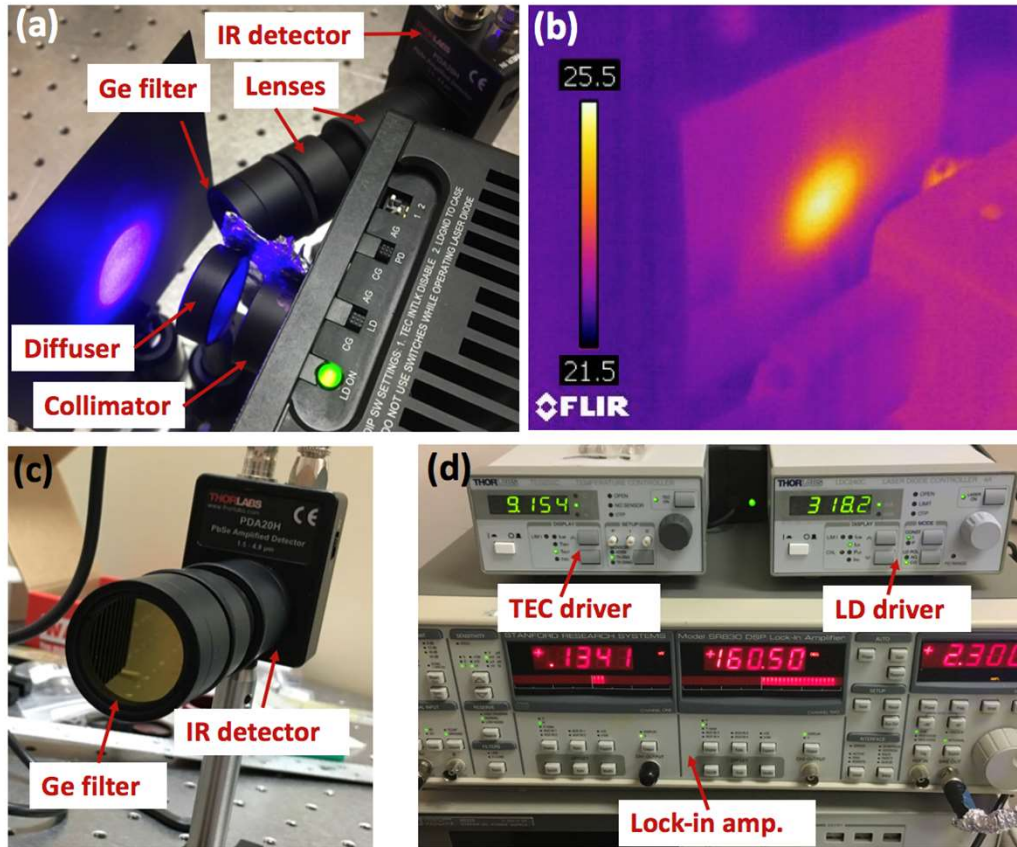
$$\theta_{s,planar}(\omega) = q_0 / \sqrt{\kappa \rho C \omega} \exp[i(\omega t - \frac{\pi}{4})]$$



[1] “Measurement of Thermal Properties of Thin Films up to High Temperatures-Pulsed Photothermal Radiometry System and Si-B-C-N Films”, Rev Sci Instrum, 2010.

[2] “Using Pulsed and Modulated Photothermal Radiometry to Measure the Thermal Conductivity of Thin Films” Thermochim Acta, 2013.

# MPR at UCSD

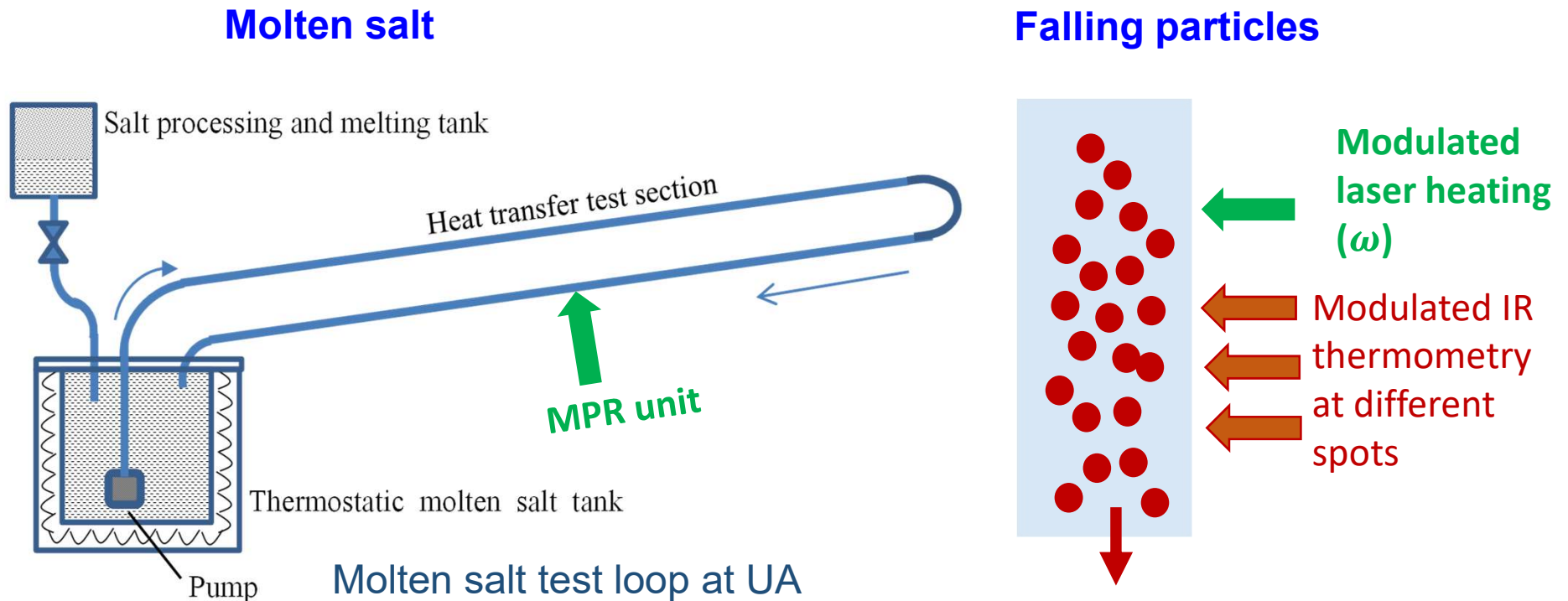


	$k \text{ (W/m-K)}$		$C \text{ (kJ/m}^3\text{-K)}$	
	Fitting	Ref	Fitting	Ref
Ni	85	90	3754	3920
SS 314	15.5	17.5	3471	3900
Acrylic	0.25	0.2	1880	1750



# MPR can also measure flowing fluids and falling particles

- Governing equation (no viscous dissipation):  $\alpha \nabla^2 T = \frac{\partial T}{\partial t} + \vec{v} \cdot \nabla T$
- With the known velocity field  $\vec{v}$ , the equation can be exactly solved.
- We will test this idea on a molten salt test loop (U Arizona) and also on falling particles



# Work Plan and Milestones

